Amendments to the Claims:

This listing of claims will replace all prior versions and listings of claims in the application:

1. (Currently Amended) A method for controlling a gap in an electrically conducting solid state structure, comprising the steps of:

providing a plurality of ~~an~~ electrically conducting features disposed on a membrane including ~~solid state structure~~ an aperture aligned with a gap between the features ~~in the structure~~;

exposing the features ~~structure~~ to a fabrication process environment conditions of which are selected to alter an extent of the gap ~~in the structure~~;

applying a voltage bias across the gap ~~in the structure~~ during process environment exposure of the features ~~structure~~;

measuring electron tunneling current across the gap during process environment exposure of the features ~~structure~~ to indicate an extent of the gap; and

controlling ~~halting~~ the process environment during process environment exposure of the features~~structure~~, based on the tunneling current measurement, to control an extent of the gap.

2. Canceled.

3. (Original) The method of claim 1 wherein controlling the process environment comprises comparing tunneling current measurement

with a threshold tunneling current corresponding to a prespecified gap extent and controlling the process environment based on the comparison.

4. (Currently Amended) The method of claim 1 wherein the conditions of the fabrication process environment are selected to increase an extent of the gap ~~in the structure~~.

5. (Currently Amended) The method of claim 1 wherein the conditions of the fabrication process environment are selected to decrease an extent of the gap ~~in the structure~~.

6. (Currently Amended) The method of claim 1 wherein the fabrication process environment comprises ion beam exposure of the features ~~structure~~.

7. (Currently Amended) The method of claim 6 wherein the ion beam exposure comprises blanket ion beam exposure of the features ~~structure~~.

8. (Original) The method of claim 6 wherein the ion beam exposure comprises rastering of the structure by a focused ion beam.

9. (Currently Amended) The method of claim 1 wherein the plurality of electrically conducting features on the membrane ~~structure~~ comprises two electrically conducting electrodes having the gap between the electrodes.

10. (Original) The method of claim 9 wherein the electrically conducting electrodes are disposed on an electrically insulating membrane including an aperture aligned with the gap between the electrodes.

11. Canceled.

12. (Canceled)
13. (Canceled)
14. (Canceled)
15. (Canceled)
16. (Canceled)
17. (Canceled)
18. (Canceled)
19. (Canceled)
20. (Canceled)
21. (Canceled)

22. (Currently Amended) The method of claim 1 wherein the fabrication process environment comprises electron beam exposure of the features ~~structure~~.

23. (Previously Presented) The method of claim 9 wherein each electrically conducting electrode is connected in a closed-loop circuit across the gap for measuring electron tunneling across the gap.

24. (Previously Presented) The method of claim 9 wherein each electrically conducting electrode is disposed in a connection to an electrical contact pad.

25. (Previously Presented) The method of claim 24 wherein applying a voltage bias across the gap in the structure comprises applying a voltage bias between the electrical contact pads.

26. (Currently Amended) The method of claim 1 wherein providing a plurality of ~~an~~ electrically conducting features disposed on a membrane ~~solid state structure~~ including an aperture aligned with a gap between the features ~~in the structure~~ comprises:

first providing an electrically conducting feature, disposed on a membrane including an aperture, ~~solid state structure~~ without a gap; and

initiating the fabrication process environment to define the plurality of electrically conducting features by forming ~~provide~~ a gap between the features in alignment with the aperture ~~in the solid state structure~~.

27. (Currently Amended) The method of claim 1 wherein providing a plurality of ~~an~~ electrically conducting features disposed on a membrane ~~solid state structure~~ including an aperture aligned with a gap between the features ~~in the structure~~ comprises:

first providing an electrically conducting feature, disposed on a membrane including an aperture, ~~solid state structure~~ without a gap; and

initiating a fabrication process environment to provide a gap in the electrically conducting feature, in alignment with the aperture, ~~solid state structure~~ that defines two electrically conducting electrodes separated from each other by the gap.

28. (Previously Presented) The method of claim 27 wherein the exposure of the structure to fabrication process environment increases the extent of the gap between the two electrically conducting electrodes.

29. (Previously Presented) The method of claim 10 wherein the electrically insulating membrane comprises a silicon nitride membrane.

30. (Currently Amended) The method of claim 1 ~~11~~ wherein the membrane is supported at its edges by a ~~substrate comprises a~~ silicon substrate.

31. (Previously Presented) The method of claim 1 wherein measuring electron tunneling current comprises amplifying acquired electron tunneling current prior to measuring electron tunneling current.

32. (Previously Presented) The method of claim 1 wherein measuring electron tunneling current comprises digitizing acquired electron tunneling current prior to measuring electron tunneling current.

33. (Currently Amended) The method of claim 1 wherein applying a voltage bias across the gap comprises applying across the gap a voltage that is less than a work function that is characteristic of the electrically conducting features ~~solid-state structure~~.

34. (Currently Amended) The method of claim 1 wherein controlling the process environment based on tunneling current measurement comprises:

determining an extent of the gap, g, as a function of measured tunneling current, I, and applied voltage bias, V, as:

$$I(V) = aV^2 e^{-b/V}$$

where $a = \frac{\sigma e^3}{16\pi^2 \phi \hbar g^2}$ and $b = \frac{4(2m_e)^{1/2}\phi^{3/2} g}{3\hbar e}$

and where σ is an area of each electrically conducting feature ~~thesolid-state structure~~ at opposite sides of the gap, e is the elementary charge, 1.6 x 10^{-19} C; $\hbar$ = 1.1 x 10^{-34} J·s; m_e = 9.1 x 10^{-31} Kg; and ϕ is a work function of the electrically conducting features ~~solid-state structure~~ at the gap; and

controlling the process environment based on the determined gap.

35. (Currently Amended) The method of claim 1 wherein controlling the process environment based on tunneling current measurement comprises:

determining an extent of the gap, g, as a function of measured tunneling current, I, and applied voltage bias, V, as:

$$I(V) = I_0 e^{-\alpha\sqrt{\phi} g}$$

where $I_0 = \frac{\sigma e^2}{4\pi^2\hbar^2}\frac{\sqrt{2m_e\phi}}{g}V$ and $\alpha = \frac{2\sqrt{2m_e}}{\hbar}$

and where σ is an area of each electrically conducting feature ~~the solid-state structure~~ at opposite sides of the gap, e is the elementary charge, 1.6 x 10^{-19} C; $\hbar$ = 1.1 x 10^{-34} J·s; m_e = 9.1 x 10^{-31} Kg; and ϕ is a work function of the electrically conducting features ~~solid-state structure~~ at the gap; and

controlling the process environment based on the determined gap.